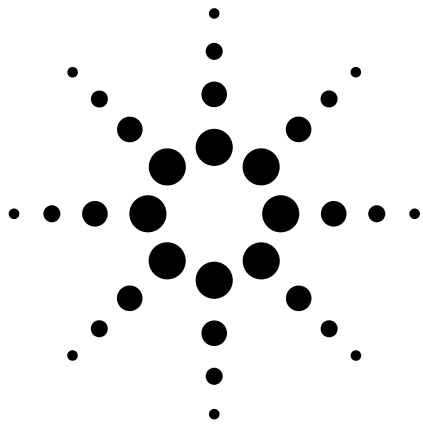




Agilent 8509B Lightwave Polarization Analyzer

Product Overview



Optical polarization
measurements of signal
and components

1200 nm to 1600 nm



Agilent Technologies
Innovating the HP Way

The Agilent 8509B Lightwave Polarization Analyzer

The Agilent 8509B lightwave polarization analyzer offers high-speed, calibrated polarization measurements of both optical signals and components. These capabilities are provided by innovations in hardware, software, and applications of Jones matrix and Stokes vector mathematics.

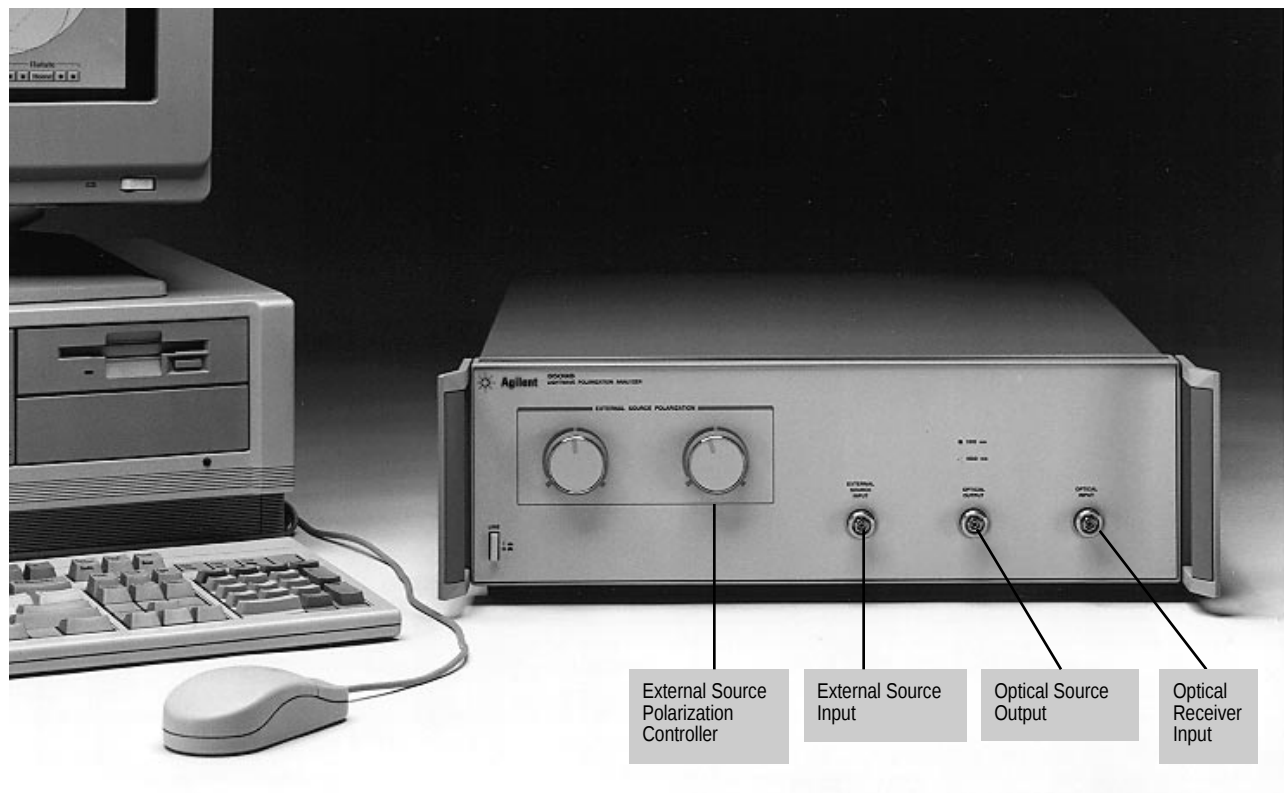
The Agilent 8509B analyzer facilitates a greater understanding of the polarization properties of lightwave signals and materials in helping to develop higher performance light-wave components and systems, as well as more effective test and manufacturing processes. These

developments involve many types of polarization-sensitive devices which are used in communications, sensors, optical computing and material analysis; devices such as single-mode fibers, polarization-maintaining fibers, isolators, optical switches, lasers, beamsplitters, modulators, interferometers, retardation plates and, of course, polarizers and polarization adjusters.

Polarization characteristics affect all lightwave transmissions. The polarization of a lightwave signal is defined by its E-field components. As a signal propagates, interaction with optical components and other lightwave signals (in interferometric

applications) modifies the magnitude and phase of the signal's E-field components. Polarization-dependent loss, gain or even signal distortion may occur depending on the application.

Polarization mode dispersion is a key hurdle limiting the transmission of signals at 10 Gbit/s and above. The Agilent 8509B lightwave polarization analyzer in conjunction with the Agilent 8168 series tunable laser source or the Agilent 83432A temperature tuned DFB laser can be used to measure PMD of fiber and components down to 1 fs resolution.



Accurate, easy-to-understand data in less time

In order to maintain a competitive edge, R&D and manufacturing operations need fast, accurate, easy-to-understand measurement data. This reduces the time and expense of bringing a product to market. The Agilent 8509B can help.

Test times are reduced by the system's versatile and powerful combination of hardware and software technology. A four-diode detection scheme delivers real-time polarization information by constantly monitoring all signal polarization states from 1200 nm to 1600 nm. Test setup is easier with the choice of using external lightwave sources or using the Agilent 8509B internal 1300 nm and 1550 nm Fabry-Perot lasers. Polarization control is available using the automatic, three-state polarization generator. Polarization mode dispersion and polarization-dependent loss measurements are quick and simple using the Agilent 8509B automatic measurement procedures.

Measurement accuracy is provided by the system's accuracy enhancement techniques. Agilent 8509B polarization reference frames enable accurate testing in bulk optics and fiber cables by removing unwanted fiber cable effects. The Agilent

8509B wavelength calibration capability automatically optimizes the system receiver for the best performance based on the polarization and wavelength of a test signal.

Polarization is easier to understand when data is presented in the appropriate display formats. When tuning the polarization of a light-wave signal, for example, the Poincare sphere is the best format because the tuning process is visually guided by a moving polarization trace on the sphere. For mathematical specifications of signal polarization, the Stokes

parameter format is best because it is used in polarization calculations. Whichever format is needed, the Agilent 8509B can meet the need with simultaneous data displays in a variety of different formats.

In the lab and on the production line, scientists, engineers and technicians depend on the speed, accuracy and convenience of the Agilent 8509B to accurately measure and predict the polarization of signals and the polarization transmission properties of components.

Agilent 8509B measurement capability and data format summary

- **Polarization Ellipse**
- **Poincare Sphere**
- **Degree of Polarization**
- **Stokes Parameters**
- **Average Power**
- **Jones Matrix**
- **Polarization Mode Dispersion**
- **Polarization-Dependent Loss**
- **Polarization-Maintaining-Fiber Launch Conditions**

Agilent 8509B

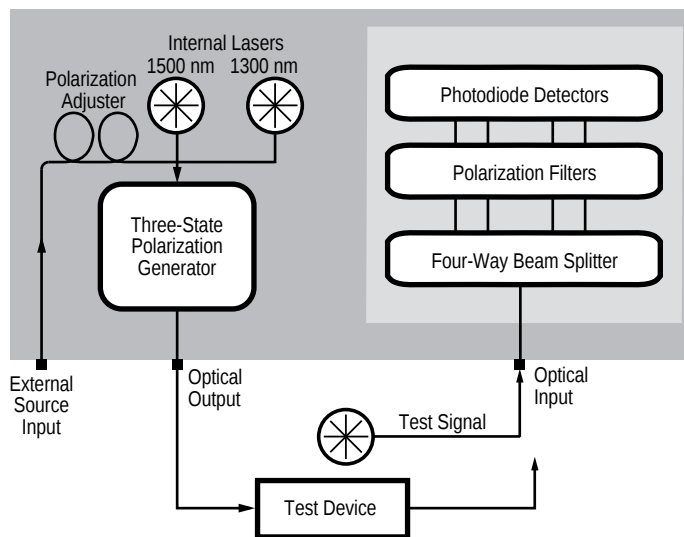


Figure 1.
Agilent 8509B block diagram

Measure optical signal polarization

Increase accuracy and make polarization easier to understand with polarization reference frame procedures and multiple, simultaneous display formats.

State of Polarization

In fiber cables and bulk-optics, the Agilent 8509B delivers high-speed signal polarization analysis by performing over 1000 polarization measurements per second. Data averaging can be applied before it is displayed as average power, polarization ellipse, Stokes parameters and points on a Poincare sphere. Three data markers provide Stokes parameter analysis and relative angle comparisons between specific data points on the Poincare sphere.

Polarization Reference Frame

Polarization reference frames are especially valuable for optical sensor and bulk-optic sub-system applications where location-specific signal polarization information is needed. In these cases the test system must remove its own responses from the test data to minimize measurement uncertainty. Improved accuracy makes measurement results easier to interpret, document and reproduce.

The Agilent 8509B quickly defines a polarization reference frame at a specific location using three polarization standards. The absolute polarization accuracy of the reference frame depends largely on the standards used.

Jones Matrix

A 2 X 2 complex Jones matrix, measured by the Agilent 8509B, mathematically describes how an individual optical component will affect the magnitude and polarization of a transmitted signal. The Jones matrices of many components can be mathematically combined. A combined Jones matrix can be used to calculate the total polarization effect that would be measured by actually connecting the components. This can be helpful when

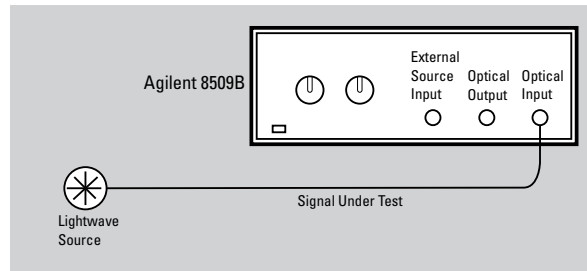


Figure 2. Signal polarization measurement setup

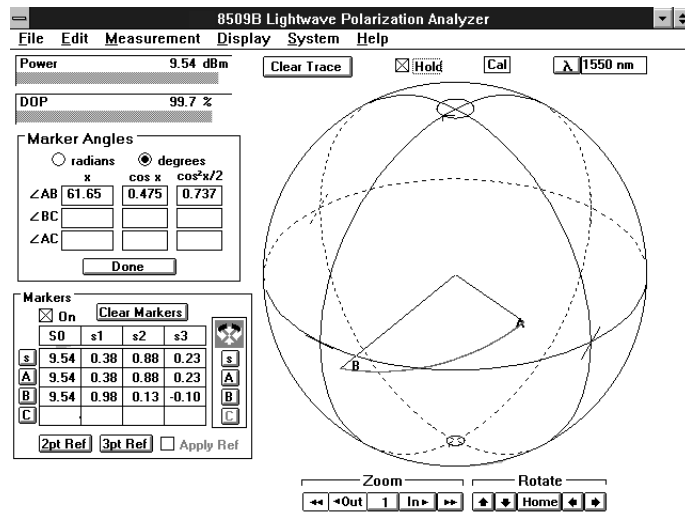


Figure 3. Angular relationships between different signal polarization states can be analyzed using Agilent 8509B Poincare sphere data markers.

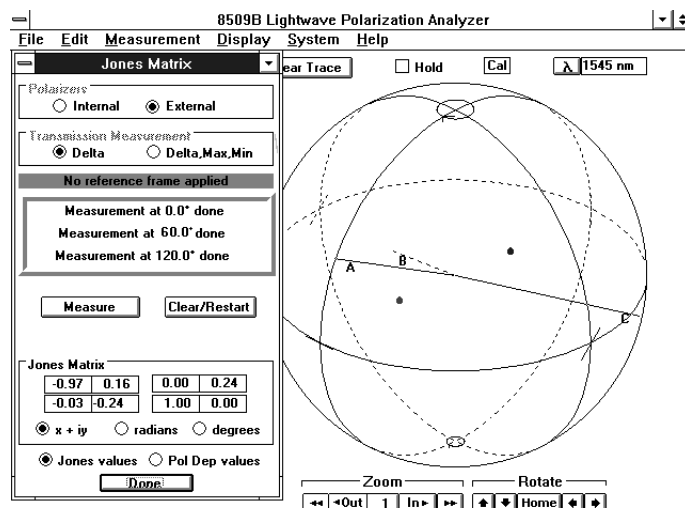


Figure 4. The Agilent 8509B displays the Jones matrix of two-port optical components and systems.

attempting to select a combination of components that will produce a certain polarization effect. Jones-matrix analysis is also used to calculate polarization mode dispersion and polarization-dependent loss of systems and components.

Measure polarization transmission properties of components

Reduce design and manufacturing uncertainties by measuring the effects of the polarization-dependent transmission properties of optical components and systems.

Polarization Mode Dispersion

Polarization mode dispersion (PMD) is an intramodal distortion mechanism (like chromatic dispersion) that causes optical devices, such as single-mode fibers, optical switches and optical isolators, to distort transmitted signals. Negative effects appear as random signal fading, increased composite second order distortion and increased digital error rates. Designers and application engineers can take action to reduce PMD and specify maximum tolerances for specific applications when PMD is quantified.

Fast, accurate and repeatable, the Agilent 8509B's automatic Jones-matrix eigenanalysis technique measures PMD with typically better than 60 fs accuracy. Jones matrices of a component are measured at consecutive wavelength steps. Sets of Jones matrices are then analyzed to calculate PMD with 1 fs resolution.

A tunable lightwave source, like the Agilent 8168D tunable laser or Agilent 83424A temperature-tuned DFB laser, is needed for this measurement and connects with the Agilent 8509B EXTERNAL SOURCE INPUT.

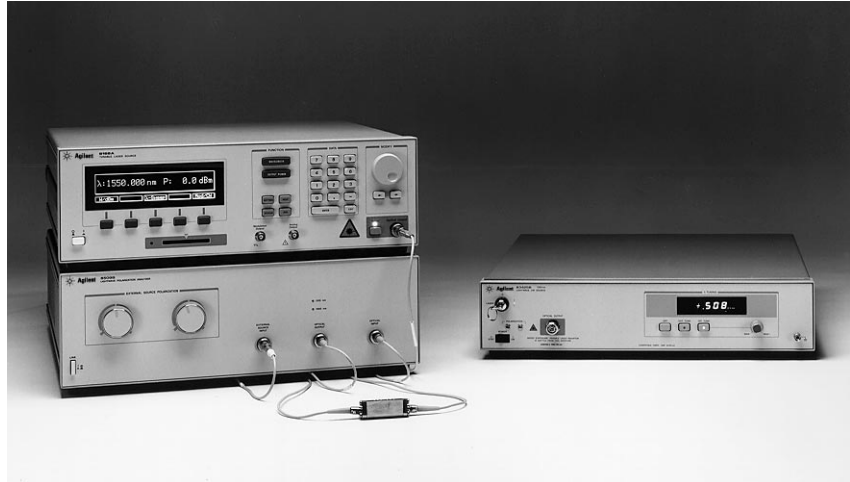


Figure 5. Polarization mode dispersion measurement setup using the Agilent 8509B and Agilent 8168 or Agilent 83424 lightwave sources.

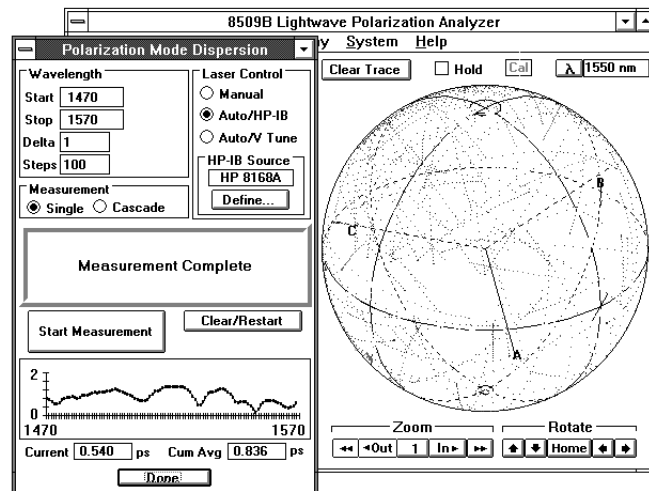


Figure 6. Polarization mode dispersion data for a 40 km length of SMF cable is shown on a graph and on the Agilent 8509B Poincaré sphere.

Measure polarization transmission properties of components

Polarization-Dependent Loss

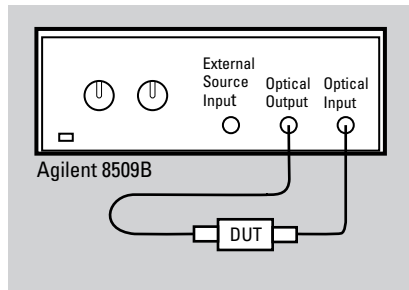


Figure 7. Polarization-dependent loss measurement setup.

Polarization-dependent loss (PDL) is a power-loss mechanism which varies as the polarization of the input signal changes. When components are connected in a system, their individual polarization-dependent losses combine to affect system performance. Chances of performance degradation are minimized by considering polarization-dependent loss in worst-case power calculations and in bit error-rate estimations.

In seconds, the Agilent 8509B uses an automated Jones-matrix technique to measure the maximum, minimum and delta optical insertion loss of a component for all possible input states of polarization. PDL markers on the Poincare sphere (Figure 8.0) show the relative location of the output states of polarization where the maximum and minimum losses occur.

Polarization-Maintaining Fiber Launch

Whenever a single-mode fiber is moved, it changes the polarization of the transmitted lightwave. A polarization-maintaining fiber, however, can deliver a linearly polarized lightwave signal regardless of its position. Maximum performance of 30 dB to 40 dB extinction ratios are only possible when linearly polarized light is correctly launched onto one of the fiber's polarization axis. Fiber alignments with 40 dB extinction ratios are easily achieved in seconds using the system's Poincare sphere display technique.

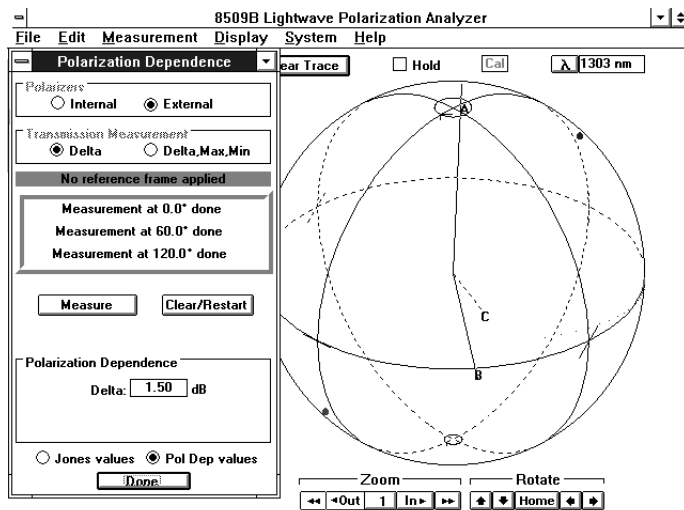


Figure 8. Polarization-dependent loss data is displayed numerically and graphically.

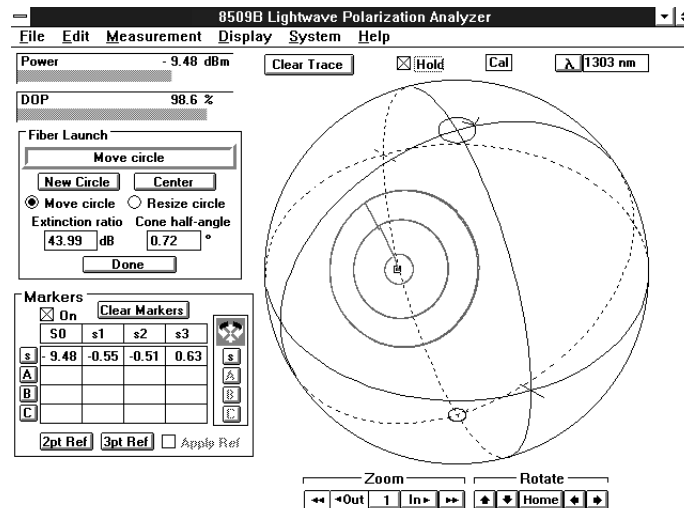


Figure 9. Typical display of polarization maintaining fiber launch alignment process.

Data Output and Remote Operation

Measurement displays and numerical data are directly output to paper or transparency using an external printer or plotter. Graphic enhancements and additional

mathematical manipulation are possible on an external computer. This can be done via GPIB data extraction or by using a disc. External controllers remotely control the Agilent 8509A/B system using GPIB.

Specifications

for the Agilent 8509B

Lightwave Polarization Analyzer

Specifications describe the instrument's warranted performance over the $23 \pm 3^\circ\text{C}$ temperature range, except where noted. All specifications apply after the instrument's temperature has stabilized (typically 1 hour after turn-on).

Characteristics provide information about non-warranted instrument performance. These are also denoted as typical.

Receiver Characteristics

Wavelength operating range: 1200 nm to 1600 nm

Input power operating range: +10 dBm to -55 dBm

Input average power damage level: +16 dBm

Average power measurement linearity: ± 0.06 dB

Average power measurement uncertainty: $\pm 15\%$

Degree of polarization measurement:

1200 nm to 1280 nm, $\pm 5.0\%$

1280 nm to 1340 nm, $\pm 2.0\%$

1470 nm to 1580 nm, $\pm 2.0\%$

1580 nm to 1600 nm, $\pm 3.0\%$

Poincare sphere display:

1200 nm to 1340 nm, ± 1.5 degrees

1470 nm to 1600 nm, ± 1.5 degrees

Polarization state measurement rate:

>1000 per second

Polarization state display update rate:

>1000 per second

Return loss: -50 dB

Agilent 8509B Internal Source Characteristics

	λ	Min	Typical	Max
Average Optical Power Output	1310 nm	200 μW	300 μW	500 μW
	1550 nm	150 μW	230 μW	400 μW
Wavelength	1310 nm		± 20 nm	
	1550 nm		± 20 nm	
Spectral width (RMS)	1310 nm		5 nm	
	1550 nm		5 nm	
Return loss	17 dB			
Laser type	Fabry-Perot			

Agilent 8509B External Source

Input Port Characteristics

Wavelength operating range: 1200 nm to 1580 nm

Internal path insertion loss: 8.5 dB

(EXTERNAL SOURCE INPUT to OPTICAL OUTPUT)

Input power operating range: +16 dBm to -49 dBm

Input average power damage level: +22 dBm

Return loss (based on OPTICAL OUTPUT connection with return loss of 30 dB or greater): 35 dB

Agilent 8509B Polarization Mode Dispersion (PMD) Specifications Using Eigenanalysis Technique

Typical wavelength operating range:

1280 nm to 1340 nm

1470 nm to 1580 nm

Warranted wavelength operating range:

1540 nm to 1560 nm.

Maximum Measurable PMD Delay:

Wavelength Step	1310 nm	1550 nm
0.01 nm	280 ps	400 ps
0.10 nm	28 ps	40 ps
1.0 nm	2.8 ps	4 ps
10.0 nm	0.28 ps	0.4 ps

Delay Uncertainty:

Wavelength Step	Uncertainty ($\pm$)
0.10 nm	310 fs
1.0 nm	90 fs
10.0 nm	60 fs

Resolution: 1 fs

Polarization Dependence Measurement Characteristics Using Jones-Matrix Analysis Technique

Wavelength operating range:

1280 nm to 1340 nm

1470 nm to 1580 nm

Measurement range: <3 dB

Uncertainty: ± 0.1 dB

Polarization-Maintaining Fiber Launch Alignment Characteristics Using Poincare Sphere Technique

Extinction ratio range: 0 dB to 50 dB

Resolution: 0.01 dB

General Specifications

Compatible fiber: 9/125 μm

Dimensions: (H x W x D)

133.4 mm x 425.5 mm x 546.1 mm

5.25 in x 16.75 in x 21.5 in

Weight (without computer and monitor):

Net : 10.5 kg (23 lbs)

Shipping: 16.0 kg (23 lbs)

Power Requirements

(without computer and monitor):

47.5 Hz to 66 Hz

90 V to 132 V or 198 V to 264 V

100 VA

Ordering Information

The Agilent 8509B polarization analyzer consists of two instrument boxes. The first contains the optical measurement hardware and the second provides the computer control.

The user interface runs on Microsoft® Windows 95 operating system.

The units are configured for optimum performance. Reconfiguring the hardware, adding to or tampering with the installed software can degrade or damage the instrument.

Table 1. Summary of Agilent 8509B measurement capabilities.

	State of Polarization	Degree of Polarization	Jones Matrix	Polarization-Dependent Loss	Polarization Mode Dispersion	Polarization Maintaining Fiber
Agilent 8509B	X	X	X*	X		X
Agilent 8509B + tunable source	X	X	X*	X	X	X

*The Agilent 8509B performs this measurement with external polarizers.

Instrument Configuration:

☐ Agilent 8509B Lightwave Polarization Analyzer

Lightwave Interface Connector Option:

Each Agilent 8509B order must be accompanied by only one of the following connector options.

- ☐ Option 011 Diamond connector
- ☐ Option 012 FC/PC connector
- ☐ Option 013 DIN 47256
- ☐ Option 014 ST connectors
- ☐ Option 015 Biconic connectors

Additional Lightwave Interface Connectors:

- ☐ Agilent 81000 AI Diamond HMS-10
- ☐ Agilent 81000 FI FC/PC
- ☐ Agilent 81000 GI D4
- ☐ Agilent 81000 KI SC
- ☐ Agilent 81000 SI DIN 47256
- ☐ Agilent 81000 VI ST
- ☐ Agilent 81000 WI Biconic

For more information about Agilent Technologies test and measurement products, applications, services, and for a current sales office listing, visit our web site,

www.agilent.com/comms/lightwave

You can also contact one of the following centers and ask for a test and measurement sales representative.

United States:

Agilent Technologies
Test and Measurement Call Center
P.O. Box 4026
Englewood, CO 80155-4026
(tel) 1 800 452 4844

Canada:

Agilent Technologies Canada Inc.
5150 Spectrum Way
Mississauga, Ontario
L4W 5G1
(tel) 1 877 894 4414

Europe:

Agilent Technologies
Test & Measurement
European Marketing Organization
P.O. Box 999
1180 AZ Amstelveen
The Netherlands
(tel) (31 20) 547 2000

Japan:

Agilent Technologies Japan Ltd.
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